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**DOI**

[10.1016/j.omx.2024.100316](https://doi.org/10.1016/j.omx.2024.100316)

**Publication date**

2024

**Document Version**

Final published version

**Published in**

Optical Materials: X

**Citation (APA)**

Dorenbos, P. (2024). Comparing thermoluminescence data on lanthanides in 36 compounds with predictions from vacuum referred binding energy diagrams. *Optical Materials: X*, 22, Article 100316. <https://doi.org/10.1016/j.omx.2024.100316>

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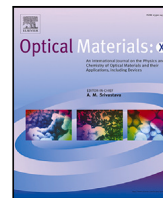
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## Invited article

# Comparing thermoluminescence data on lanthanides in 36 compounds with predictions from vacuum referred binding energy diagrams

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## ARTICLE INFO

## Keywords:

Luminescence  
Phosphors  
Scintillators  
Quantum dots  
Nanomaterials  
OLED  
Glasses  
Electroluminescence

## ABSTRACT

Thermoluminescence (TL) often involves the liberation of a charge carrier (an electron or a hole) from a charge carrier trapping centre into the conduction band (CB) or the valence band (VB) with subsequent recombination with a counter charge carrier at a luminescence centre. TL glow peak analysis can provide the energy  $\Delta E_i$  needed to liberate such charge carrier which then defines the location of the charge transition levels (CTL) of the carrier trapping centres below the CB-bottom or above the VB-top. The temperature at the maximum of the TL glow peak changes 3–4 K per 0.01 eV change in  $\Delta E_i$ , thus providing an extremely sensitive probe of energy changes in CTLs. This work collects and reviews data on glow peaks due to electron or hole release from lanthanide dopants in 36 different inorganic compounds. To compare results from different literature sources, data were always re-analysed using the same method that is solely based on the temperature at the maximum of the glow peak. The changes in  $\Delta E_i$  along the lanthanides series provides insight at the sub 0.1 eV level on the changes in CTL energies. We will use a compound-dependent parameter to account for the nephelauxetic effect and a compound dependent parameter to account for lattice relaxation around the lanthanide. Together with information from lanthanide luminescence spectroscopy, the vacuum referred binding energy (VRBE) diagram will be constructed for each compound. The lanthanide electron or hole trap depth read from the VRBE scheme will be compared with that derived from the TL glow peak. Surprisingly good agreement will be demonstrated.

## 1. Introduction

The functioning of optical and electronic materials is usually connected to how electrons are transferred between electronic states of the material. This is evident for luminescence phosphors where electrons undergo optical transitions between quantum states of the luminescent species as illustrated for  $Tb^{3+}$  with arrows (a) and (b) in Fig. 1. Electron transitions from the valence band (VB) to the conduction band (CB), arrow (1), defines the window of transparency and the bandgap of insulating materials. In solid state batteries, the flow of electrons in the external circuit, the flow of ions through the electrolyte, and attainable battery voltage is intimately connected with the energy involved in reduction and oxidation of the electron storing species [1]. The efficiency of photocatalytic splitting of water into oxygen and hydrogen depends on the location of the VB and CB of the photo-anode with respect to the redox potentials of water [2]. One needs to know the binding energy of a charge carrier during each stage to understand the functioning of the material.

In this work we will limit the discussion to the lanthanide-activated inorganic family of compounds. These are materials that are widely used for application such as luminescent phosphor in lighting systems,

as laser crystals, scintillation crystals for the detection of ionizing radiation, charge carrier storage phosphors utilized either as afterglow phosphors, dosimetry phosphors for radiation monitoring, or X-ray storage phosphors in, for example, dental imaging [3,4]. Thermal quenching of luminescence is often controlled by the location of the emitting state with respect to the CB-bottom or the VB-top of the host compound [5]. The charge carrier (an electron or a hole) trapping depth is given by the location of the ground state of the trapping centre with respect to the CB or VB and can be determined with thermoluminescence (TL) techniques [6–8]. In order to understand and to utilize luminescence and carrier trapping phenomena we then need to know the binding energy of an electron in the relevant states with respect to that in the host bands. A most unique property of the lanthanides is that with the filling of the 4f-orbital with at most 14 electrons, the binding energies in the 4f ground states always follow a similar zigzag shape pattern. This is illustrated in Fig. 1.

Vacuum referred binding energy (VRBE) diagrams with the divalent and trivalent lanthanide level energies have gained popularity in the past decade because of their high predictive and explanatory potential. The VRBEs in the lanthanide ground state levels are equivalent to the

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<https://doi.org/10.1016/j.omx.2024.100316>

Received 17 January 2024; Received in revised form 6 March 2024; Accepted 4 April 2024

Available online 6 April 2024

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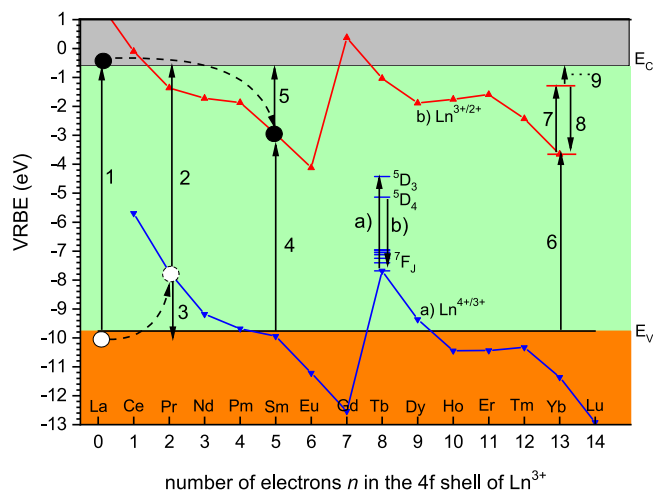


Fig. 1. Vacuum referred binding energy diagram with the location of curve (a) the  $\text{Ln}^{4+/3+}$  and curve (b) the  $\text{Ln}^{3+/2+}$  charge transition levels connected with characteristic zigzag solid curves. The arrows indicate various charge carrier transitions that can be experimentally observed.

$\text{Ln}^{3+/2+}$  and  $\text{Ln}^{4+/3+}$  charge transition levels (CTL), and they vary in a systematic and thus predictable fashion. At the start of the development of host referred binding energy (HRBE) diagrams [9] and later the VRBE-diagrams [10] various pieces of information on electronic transitions involving lanthanides were combined. Arrows (4) and (6) in Fig. 1 indicate electron transitions from the VB-top to  $\text{Sm}^{3+}$  and  $\text{Yb}^{3+}$  thus defining the  $\text{Sm}^{3+/2+}$  and  $\text{Yb}^{3+/2+}$  CTLs above the VB-top. Likewise arrow (2) indicating direct excitation of an electron from  $\text{Pr}^{3+}$  to the CB, defines the  $\text{Pr}^{4+/3+}$  CTL below the CB-bottom. Arrow (9) indicates the energy barrier for thermal quenching of  $\text{Yb}^{2+}$  5d-4f emission due to thermal ionization of the excited state 5d-electron to the CB. Arrow (3) indicates the energy needed to liberate a hole from  $\text{Pr}^{4+}$  to the VB, and arrow (5) to liberate an electron from  $\text{Sm}^{2+}$  to the CB as can be obtained from TL studies. Combining such information enables the unravelling of the systematics behind lanthanide CTLs. Now that the method of VRBE-diagram construction is well established, such diagrams can be exploited to predict properties like the energy of charge transfer (CT) bands, the thermal quenching of lanthanide emission, the preferred valence state of a lanthanide, the depth of the electron trap or the hole trap provided by a lanthanide. VRBE-diagrams also provide insight in the VRBE at the conduction band bottom and valence band top and how those change between compounds. This is nowadays frequently utilized in bandgap engineering of phosphor properties, see e.g. [11–13].

It is quite remarkable that with few experimentally determined values, one may already construct a VRBE diagram having all the lanthanide CTLs. The method of VRBE-construction is based on various assumptions, but it is however not yet well established whether those assumptions hold for all type of compounds (halides, oxides, sulphide etc.) alike. Ideally, the energies involved in transitions 3 and 2, 4 and 5, and 6, 7 and 9 in Fig. 1 should all add up to that of transition (1). To spot shortcomings in VRBE-diagram construction, the energy barrier  $\Delta E_q$  of thermal quenching of lanthanide luminescence was compared with predictions from a VRBE diagram in [5]. In this work we augment that study with the charge carrier trapping depths  $\Delta E_t$  obtained from TL. Fig. 1 shows that many of the trivalent lanthanides may trap an electron and TL can then probe the energy needed to liberate such electron into the conduction band as illustrated for  $\text{Sm}^{2+}$  with transition (5). The trivalent lanthanides  $\text{Ce}^{3+}$ ,  $\text{Pr}^{3+}$  and  $\text{Tb}^{3+}$  are often able to trap a hole and then TL can probe the location of the  $\text{Ln}^{4+/3+}$  CTL above the VB. Suppose we excite optically an electron from the VB-top to a  $\text{Ln}^{3+}$ , one then obtains the location of the  $\text{Ln}^{3+/2+}$  CTL above the VB-top. One might also first charge the phosphor by trapping an electron from the

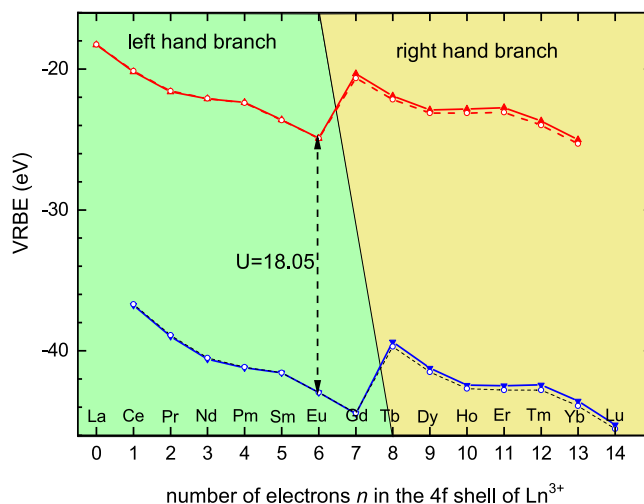


Fig. 2. Free lanthanide CTL-curves as function of the number of electrons in the 4f-orbital. The dashed curve is obtained when inter-electron repulsion is reduced by 6%, i.e., when  $\beta = 0.94$ . The curves with reduced repulsion are normalized such that for Eu the CTLs coincide with the free ion Eu CTLs. Changes on the left-hand branch are marginal but the right-hand branch is lowered by  $\approx 0.3$  eV.

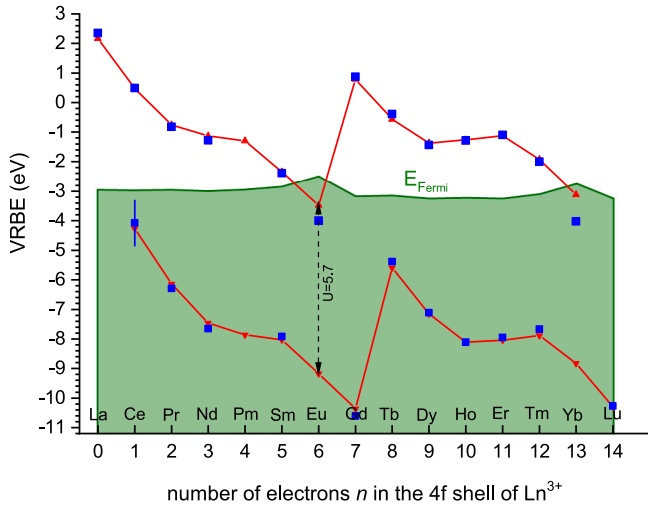
CB in that same  $\text{Ln}^{3+}$  to obtain the location of that same  $\text{Ln}^{3+/2+}$  CTL below the CB-bottom. Ideally, knowing the band gap of the compound both CTLs should coincide. However, one may think of many reasons why it will not be ideal. Do we really optically excite from the VB-top or are there also transitions from somewhere deeper in the VB? With TL we start from a trapped electron state at  $\text{Ln}^{2+}$  with a fully relaxed lattice around it whereas after CT we end in an unrelaxed state at  $\text{Ln}^{2+}$ . How will lattice relaxation affect the CTL? Is it really needed that the charge carrier during TL-readout transports via the CB or VB or is some lower energy route possible? By collecting and analysing TL data involving electron and/or hole release from lanthanides we aim to confirm the VRBE schemes or otherwise spot systematic errors.

## 2. Theory and experimental methods

In this section, first the theory and main idea behind the Chemical Shift model to construct VRBE diagrams will be reviewed. The equations, parameters, and experimental input parameters needed for VRBE construction will be presented. Next the Arrhenius equation describing thermal quenching of luminescence and the Randall-Wilkins equation describing a TL glow peak are treated.

### 2.1. The chemical shift model and lanthanide charge transition levels

To understand charge transition level energies of the lanthanides in compounds one first needs to treat them as free ions in vacuum. By definition the energies of the free ion  $\text{Ln}^{3+/2+}$  CTLs are the same as minus the 3rd ionization potentials of the lanthanides. Likewise the free ion  $\text{Ln}^{4+/3+}$  CTLs are minus the 4th ionization potentials. As illustrated in Fig. 2 the free ion CTLs follow a characteristic double seated zigzag curve with the number of electrons in the 4f-orbital. The shape arises from the Coulomb repulsion between the 4f-electrons when the lanthanides are in their  $2s+1 L_J$  ground states. The repulsion energies can be obtained from the radial part of the 4f-orbital functions using the refined spin pairing theory of Jørgensen [14,15] together with the experimental Slater–Condon parameters [16,17]. Fig. 2 illustrates what happens with the free ion CTL shapes when the 4f-4f inter electron repulsion is reduced by 6%. For  $n < 8$ , i.e., the left-hand branch of the CTL curve, change in CTL is insignificant. However, for  $n > 7$  defining the right-hand branch, the entire branch is lowered by  $\approx 0.3$  eV.



**Fig. 3.** The  $\text{Ln}^{3+/2+}$  and  $\text{Ln}^{4+/3+}$  CTLs in the pure lanthanide metals as derived from photoelectron spectroscopy when CTLs are below the Fermi level, and inverse photoelectron spectroscopy when they are above. The Fermi energy  $E_F$  is obtained from reported values for the work function. See [10] for further details. The solid curves connect the CTLs obtained with the RCS-model using  $U = 5.7$  eV,  $\beta(2+) = \beta(3+) = 0.91$ ,  $f(2+) = f(3+) = 0.68$  corresponding with  $\alpha(2+) = 0.11$  eV/pm and  $\alpha(3+) = 0.18$  eV/pm.

Let us now place the lanthanides in a compound. The positively charged lanthanides will then be surrounded by negative charge which adds a Coulomb repulsion to the 4f-electrons. As a result, the entire CTL curve is moved upwards with an amount known as the chemical shift. The Chemical Shift model states that a divalent lanthanide is effectively surrounded (screened) by 2- electronic charge at average screening distance close to the lanthanide ionic radius, and a trivalent lanthanide likewise by 3- electronic charge [10]. The chemical shift for trivalent lanthanides is then roughly 3/2 larger than for divalent ones. This implies that the energy difference between the two CTL curves will decrease when in compounds. The absolute size of the chemical shift depends on how close the surrounding screening charge can approach the lanthanide, i.e., the screening distance. Screening is most perfect, and approach is most close in the pure lanthanide metals where the di- or trivalent lanthanide cation is surrounded by 2 or 3 free conduction band electrons in each unit cell of the metal. Chemical shift will then be maximum with minimum energy separation between the two CTL curves.

Fig. 3 shows the CTLs of the lanthanides in the pure lanthanide metals. Data points below the Fermi level were derived from photoelectron spectroscopy and above from inverse photoelectron spectroscopy. Data were reviewed and analysed in [10]. The two solid zigzag curves connecting the CTLs obtained with the Refined Chemical Shift (RSC) model [16,17]. We will express the separation between the two CTL curves with the  $U$ -value for Eu, defined as the energy difference between the CTL of  $\text{Eu}^{3+/2+}$  and  $\text{Eu}^{4+/3+}$ . It is 18.05 eV in vacuum as in Fig. 2 and has reduced to  $(5.7 \pm 0.1)$  eV for Eu-metal in Fig. 3.

In inorganic compounds, the surrounding electrons are bonded in the anions and the anions are bonded in the crystalline lattice. This bonding will resist the free movement of surrounding screening charge and the chemical shift will be smaller and the  $U$ -value larger than for metals. The  $U$ -value for a compound can be derived when sufficient spectroscopic data is available for several different lanthanides in the same compound. It appears largest (7.6–7.4 eV) for fluoride compounds where electrons are strongly bonded in the highly electronegative fluorine [18,19]. It decreases progressively with weaker bonding of the electrons and anions until the limiting case of 5.7 eV for the lanthanide metals is reached. Although  $U$  can be determined experimentally, it has proved very difficult to establish the chemical shift and therewith the energies of the CTLs with respect to the vacuum level.

Matters changed with the development of the Chemical Shift model published in 2012 [10,20]. The model not only explains the origin of chemical shift and how it depends on compound properties but also proposes the following relation between the  $U(A)$ -value for compound  $A$  and the size of the chemical shift,

$$CTL(\text{Eu}^{3+/2+}, A) = -24.92 + \frac{18.05 - U(A)}{0.777 - 0.0353U(A)} \quad (1)$$

and

$$CTL(\text{Eu}^{4+/3+}, A) = CTL(\text{Eu}^{3+/2+}, A) - U(A) \quad (2)$$

where the last term in Eq. (1) is the chemical shift  $E_{cs}(\text{Eu}, 2+, A)$  of the  $\text{Eu}^{3+/2+}$  CTL in compound  $A$ , and 24.92 eV is the third ionization potential of Eu. In [16,17] everything was put together in one equation to represent all  $\text{Ln}^{4+/3+}$  and  $\text{Ln}^{3+/2+}$  CTL energies

$$\begin{aligned} CTL(\text{Ln}^{Q+1/Q}, A) = & C(q, Q) + \beta(Q, A)S(q, Q) + (1 - \beta(Q, A))S(\text{Eu}, Q)) \\ & + E_{cs}(\text{Eu}, Q, A) \\ & + \alpha(Q, A)(R(\text{Eu}, Q) - R(q, Q)) \end{aligned} \quad (3)$$

where  $q$  the number of electrons in the 4f-orbital.  $S(q, Q)$  is a function that accounts for the main features in the CTL curves of the free lanthanides and that has been calculated by combining Jørgensen spin pairing theory with experimentally derived Slater–Condon  $F^k$  parameters [16].  $C(q, Q)$  appears a smoothly decreasing function with increasing  $q$  and obtained by subtracting  $S(q, Q)$  from the ionization potentials, see Fig. SI-1 and Fig. SI-2.  $R(q, Q)$  are the ionic radii of the lanthanides.  $R(\text{Eu}, Q)$  represents the ionic radius  $R(6, 3+)$  in case of  $\text{Eu}^{3+}$  or  $R(7, 2+)$  in case of  $\text{Eu}^{2+}$ .  $C(q, Q)$ ,  $S(q, Q)$ ,  $R(q, Q)$  are constants that were tabulated in [16,17] and reproduced in Table 1. In the case  $\text{Ln}=\text{Eu}$ , Eq. (3) becomes identical to Eq. (1) for  $Q = 2+$  and Eq. (2) for  $Q = 3+$ . The parameter  $\beta(Q, A)$  accounts for the nephelauxetic effect.  $\beta = 1$  for the free lanthanides, 0.94 for the example in Fig. 2, and 0.91 for the lanthanide metals in Fig. 3. In this work we will frequently use as first estimate for  $\beta(2+)$  and  $\beta(3+)$

$$\beta(2+, A) = \beta(3+, A) = 0.656 + 0.04 \times U(A) \quad (4)$$

$\alpha(Q, A)$  are the contraction tilt parameters in eV/pm. The function  $C(q, Q)$  might change slightly with chemical environment although it is expected to remain a smoothly decreasing function with  $q$ . Unfortunately, this cannot be tested experimentally. We will therefore use the  $C(q, Q)$  values in Table 1 for all environments and a slight dependence with  $A$  is then absorbed in the value for  $\alpha(Q, A)$  and chemical shift. Note that the term  $(1 - \beta(Q, A))S(\text{Eu}, Q)$  in Eq. (3) was absent in the equations presented in [16,17]. That omission was a mistake, but fortunately in all VRBE diagrams presented after introduction of the RCS-model the correct Eq. (3) was used.

Fig. 4 shows the CTLs of the lanthanides when  $U = 7.09$  eV which applies for  $\text{YPO}_4$ . The chemical shift for  $\text{Eu}^{2+}$  amounts 20.8 eV and for  $\text{Eu}^{3+}$  it is 31.8 eV. Their ratio of 1.53 is close to 3/2. To arrive at the CTLs for the other lanthanides, we need to account for the lanthanide contraction. In going from La to Lu, the ionic radius decreases by about 12% [21] as can be seen in Table 1. When the lanthanide is placed on a site in a compound, the surrounding screening charge can approach the smaller lanthanide more closely than the larger one. The chemical shift will then increase with smaller size of the lanthanide. Assuming that the effect is linear with the ionic radius, the entire CTL-curve will be tilted counter clockwise as illustrated in Fig. 4. This tilting is expressed with the contraction tilt parameters  $\alpha(Q, A)$  in the last term of Eq. (3). In [10], the contraction tilt in eV/pm and the Eu chemical shift  $E_{cs}(\text{Eu}, Q, A)$  were related as

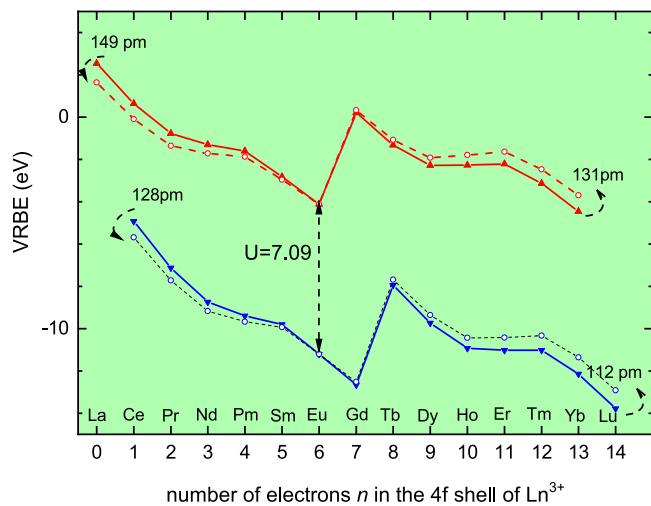
$$\alpha(Q, A) \approx \frac{f(Q, A)}{1440Q} (E_{cs}(\text{Eu}, Q, A))^2 = \frac{f(Q, A)}{1440Q} \left( \frac{18.05 - U(A)}{0.777 - 0.0353U(A)} \right)^2 \quad (5)$$

The relaxation fractions  $f(Q, A) < 1$  were introduced because in lanthanide doped inorganic compounds, lattice relaxation does not

**Table 1**

The energies  $C$  and  $S$ , and the lanthanide ionic radii  $R$  needed to compute the  $\text{Ln}^{4+/3+}$  and  $\text{Ln}^{3+/2+}$  charge transition level energies with the refined Chemical Shift model.  $q$  is the number of electrons in the 4f-orbital of the divalent lanthanides and  $n$  in the trivalent ones. Energies are in eV and radii in pm.

q	n	Ln	$R(q, 2+)$	$R(n, 3+)$	$C(q, 2+)$	$S(q, 2+)$	$C(n, 3+)$	$S(n, 3+)$
1	0	La	148.7	–	–18.170	–0.116	–	–
2	1	Ce	147.0	128.26	–19.723	–0.475	–36.591	–0.167
3	2	Pr	145.3	126.58	–21.087	–0.537	–38.370	–0.610
4	3	Nd	143.7	124.97	–22.325	0.223	–39.895	–0.705
5	4	Pm	142.2	123.42	–23.331	0.962	–41.387	0.187
6	5	Sm	140.7	121.94	–24.390	0.789	–42.627	1.072
7	6	Eu	139.3	120.53	–25.249	0.329	–43.870	0.900
8	7	Gd	137.9	119.19	–25.901	5.566	–44.852	0.402
9	8	Tb	136.6	117.91	–26.535	4.625	–45.792	6.422
10	9	Dy	135.4	116.7	–27.084	4.194	–46.712	5.487
11	10	Ho	134.3	115.55	–27.809	4.969	–47.524	5.089
12	11	Er	133.2	114.47	–28.569	5.829	–48.478	5.998
13	12	Tm	132.2	113.46	–29.243	5.563	–49.375	6.955
14	13	Yb	131.3	112.52	–29.913	4.883	–50.191	6.631
–	14	Lu	–	111.7	–	–	–51.066	5.816



**Fig. 4.** CTL curves for  $U = 7.09$  eV and  $\beta(3+) = 0.94$  and  $\beta(2+) = 0.95$ . The solid curves are without tilt correction or  $\alpha(2+) = \alpha(3+) = 0$ . The dashed curves are with  $\alpha(2+) = 0.095$  eV/pm and  $\alpha(3+) = 0.098$  eV/pm causing a slight counter clockwise rotation due to the lanthanide contraction. The ionic radius of the lanthanides at the start and end of the CTL curves are provided.

fully compensate for the ionic radius difference between the lanthanide and the cation it has substituted for. For the pure lanthanide metals in Fig. 3, we used  $f(2+, \text{metal}) = f(3+, \text{metal}) = 0.68$  yielding  $\alpha(2+, \text{metal}) = 0.11$  eV/pm and  $\alpha(3+, \text{metal}) = 0.18$  eV/pm where the ratio of 1.64 is slightly larger than 3/2. For the compounds of this work we will find that with  $f(2+, A)$  in the range 0.58–0.72 and  $f(3+, A)$  in the range 0.42–0.45 good agreement with available experimental data from TL studies is obtained.

With Eq. (5), Eq. (1), Eq. (2), and Eq. (4), we arrive at a situation that we need only the  $U(A)$  value and the two  $f(Q, A)$  values for our compound to establish all  $\text{Ln}^{3+/2+}$  and  $\text{Ln}^{4+/3+}$  CTL energies in that compound. Next task is to find the VRBE at the VB-top and the CB-bottom. There are many techniques to establish those energies with respect to the lanthanide CTL. Most important method is to use the so-called charge transfer (CT) band energy  $E^{CT}(\text{Eu}^{3+}, A)$  that appears in the excitation spectra of  $\text{Eu}^{3+}$  emission. Here an electron is transferred from the top of the VB to  $\text{Eu}^{3+}$  that is then converted into  $\text{Eu}^{2+}$ . The VRBE  $E_V$  at the VB-top is then given by

$$E_V(A) = CTL(\text{Eu}^{3+/2+}, A) - E^{CT}(\text{Eu}^{3+}, A). \quad (6)$$

Information on  $\text{Eu}^{3+}$  is most abundant but one may equally well use the CT-band energy to another trivalent lanthanide like indicated by

arrows (4) and (6) in Fig. 1, and use the CTL for that lanthanide instead. However, in presenting the parameters used in VRBE construction we will always specify the value for the VB→ $\text{Eu}^{3+}$  CT either measured for  $\text{Eu}^{3+}$  or derived from the CT energy to another  $\text{Ln}^{3+}$  by using the shape of the CTL curve as given by Eq. (3). To arrive at the VRBE at the CB-bottom we must add the mobility band gap energy to  $E_V$

$$E_C(A) = E_V(A) + E^{ex}(A) + 0.008(E^{ex}(A))^2 \quad (7)$$

where  $E^{ex}(A)$  is the energy of exciton creation and  $0.008(E^{ex})^2$  an empirical estimate for the electron-hole binding energy in the exciton as was proposed in [22].

The effect of temperature on CTL energies has been disregarded in the past. However, the glow peak temperature in TL recordings may cover a temperature range of 100 to 1000 K and the same applies to the thermal quenching temperature of lanthanide luminescence. Then in order to use derived trapping depths and quenching energy barriers to verify VRBE schemes one may not disregard temperature anymore. Due to lattice expansion and electron phonon interaction, the CTL energies of the lanthanides and that of  $E_V$  and  $E_C$  depend on temperature. This aspect was studied in Ref. [23] where it was found that cation CTLs move down and anion CTLs move up by several 0.1 eV when temperature increases from 10 K to RT. The transitions labelled (1), (3), (4), and (6) in Fig. 1 all concern charge carrier transfer between an anion and a cation. Those energies decrease slightly when temperature increases. This was demonstrated by comparing experimental data on  $E^{ex}$  and on  $E^{CT}(\text{Eu}^{3+})$  at 10 K and RT. The temperature dependence of  $E^{CT}$  can roughly be represented by

$$E^{CT}(T) = E^{CT}(293\text{K}) - 6 \times 10^{-4}(T - 293). \quad (8)$$

Although there appears quite some compound-to-compound variation in that dependence, we will use this equation to correct values to the RT situation.

The transitions labelled (2), (5), (9) concern electron transfer between a lanthanide cation and the cation derived states at the CB-bottom. The energies of those states shift in the same direction when temperature changes. Although they shift not necessarily in the same pace, we will assume that the transition energies are independent on temperature and there is no need for correcting to the RT situation.

In using the parameter  $E^{CT}$  employed for VRBE construction there was never attention for the temperature. Usually, an average value from data reported in literature was taken that may be at RT or at lower temperature. For  $E^{ex}$  usually the value pertaining around 10 K was used. With such method errors of the order of few 0.1 eV are introduced in the VRBE scheme which was thought acceptable considering other errors in VRBE construction. Anyway, all VRBE schemes of this work will be based on the  $E^{ex}$  and  $E^{CT}$  values that pertain to RT. Whenever experimental data were measured at another temperature, they were corrected to the RT values using the findings in [23].

Finally we have arrived at the three main parameters  $U(A)$ ,  $E^{CT}(\text{Eu}^{3+}, A)$ , and  $E^{ex}(A)$  pertaining to 293 K that provide all necessary information to construct the room temperature VRBE scheme for compound  $A$  with  $E_V$ ,  $E_C$ , and the  $\text{Eu}^{3+/2+}$  and  $\text{Eu}^{4+/3+}$  CTLs. The values for  $\beta(Q, A)$  and  $f(Q, A)$  are then needed together with Eqs. (3) and (5) to obtain the CTLs for all other lanthanides than Eu.

## 2.2. The Arrhenius and Randall-Wilkins equation

In [5], the quenching of lanthanide  $4f^n-4f^n$  emission due to thermally activated electron transfer from the  $\text{Pr}^{3+} {}^3P_0$  level and the  $\text{Tb}^{3+} {}^5D_4$  level to the conduction band, and due to thermally activated hole transfer from the  $\text{Eu}^{3+} {}^5D_0$  level to the valence band was studied. In addition the quenching of  $4f^{n-1}5d-4f^n$  emission of  $\text{Eu}^{2+}$  and  $\text{Ce}^{3+}$  which often (if not always) proceeds by electron transfer to the conduction band was studied. In all five cases the quenching involves a charge carrier transfer from an excited state to  $E_V$  or  $E_C$ , and then the energy difference between the lanthanide CTLs and  $E_V$  or  $E_C$  is crucial. The

**Table 2**

The dependence of  $T_{50}$  on the activation energy  $\Delta E_q$  in K/eV calculated for  $\Gamma_0 = 2 \times 10^{13}$  Hz and using the typical value for  $\tau_v$  in column 4. The bottom row relates to lanthanide TL glow peaks in  $\text{YPO}_4$  where  $T_m/\Delta E_t = 314$  K/eV when the heating rate  $\beta = 0.1$  K/s. Column six compiles the energy offset values in eV.

A	Transition	$\lambda(\text{nm})$	$\tau_v$	$T_{50}/\Delta E_q$	$\Delta E_{\text{offset}}$
$\text{Ce}^{3+}$	$5d \rightarrow 4f[{}^2F_{5/2,7/2}]$	300–550	40 ns	850	$0.0 \pm 0.2$
$\text{Eu}^{2+}$	$5d \rightarrow 4f[{}^8S_{7/2}]$	380–600	1000 ns	690	$-0.15 \pm 0.15$
$\text{Pr}^{3+}$	${}^3P_0 \rightarrow {}^3H_{4,5,6}$	490, 550, 620	50 $\mu\text{s}$	560	$0.3 \pm 0.15$
$\text{Tb}^{3+}$	${}^5D_4 \rightarrow {}^7F_5$	$\approx 545$	2 ms	475	$0.5 \pm 0.15$
$\text{Eu}^{3+}$	${}^5D_0 \rightarrow {}^7F_{1,2}$	$\approx 610$	2 ms	475	$0.45 \pm 0.12$
TL	$\text{YPO}_4$	$G = 14.6$	$\beta = 0.1$	314	–

aim of [5] was twofold; (i) to derive the quenching energy barrier  $\Delta E_q$  from published luminescence data by using the Arrhenius equation, (ii) to explore if and how it agrees with prediction from constructed VRBE schemes employing the RCS-model. In this work we will employ published TL data with similar aims; (i) to derive the charge carrier trapping depths  $\Delta E_t$  by using the Randall-Wilkins equation describing a TL glow peak, and (ii) to explore if or how it agrees with prediction from constructed VRBE schemes employing the RCS-model. The combined studies give a strong experimental support for the method of VRBE construction but also reveals the limitations of the method.

The thermal quenching of luminescence intensity  $I(T)$  is traditionally expressed with the single energy barrier Arrhenius equation

$$I(T) = \frac{I(0)}{1 + \frac{\Gamma_0}{\Gamma_v} \exp\left(\frac{-\Delta E_q}{kT}\right)} \quad (9)$$

where  $\Gamma_v$  is the radiative decay rate,  $\Gamma_0$  is the attempt rate for thermal quenching which is assumed to have similar magnitude as the maximum phonon frequency in compounds,  $k$  is the Boltzmann constant. However, in the case when there is not a single energy barrier  $\Delta E_q$  but instead a barrier height distribution, Eq. (9) will provide wrong results. In the presence of a symmetrical distribution, the quenching curve shape will become less steep but the temperature  $T_{50}$  where luminescence intensity has dropped by 50% remains practically the same. Rather than fitting quenching curves with Eq. (9) it is then better to choose a reasonable value for  $\Gamma_0$  based on the composition of the compound, and then derive  $\Delta E_q$  from the temperature  $T_{50}$ . For that, equation

$$T_{50} = \frac{11600}{\ln(\tau_v \Gamma_0)} \Delta E_q \quad (10)$$

applies where  $\tau_v = 1/\Gamma_v$ . Now we should interpret  $\Delta E_q$  as the average energy of the distribution.

Table 2 shows the studied transitions of the five lanthanides in [5] with the typical decay times. With longer decay time Eq. (10) predicts the rate of change of  $T_{50}$  with  $\Delta E_q$  to decrease. For the fast decay  $5d\text{-}4f$  emission of  $\text{Ce}^{3+}$  it is as large as 850 K/eV and for the slow decay of the  $4f\text{-}4f$  emission in  $\text{Tb}^{3+}$  and  $\text{Eu}^{3+}$  it reduces to 475 K/eV. In [5] data on  $T_{50}$  was gathered from the archival literature covering more than 170 different compounds. For each compound, the quenching energy barrier  $\Delta E_q$  was determined from a constructed vacuum referred binding energy diagram (VRBE). Data were reanalyzed for  $\text{Eu}^{3+}$  in [23]. For  $\text{Eu}^{3+}$ ,  $\text{Pr}^{3+}$ , and  $\text{Tb}^{3+}$ , the data follow the predicted rate of change reasonably well. For  $\text{Eu}^{2+}$  and  $\text{Ce}^{3+}$  correlation was less evident because of strong scatter of data points.

When  $T_{50}$  approaches 0 K, one expects the quenching energy barrier  $\Delta E_{\text{VRBE}}$  as read from the VRBE diagram to approach zero too. However, experimentally an offset energy  $\Delta E_{\text{offset}}$  is observed and

$$\Delta E_{\text{VRBE}} = \Delta E_{\text{offset}} + \frac{T_{50} \ln(\tau_v \Gamma_0)}{11600}. \quad (11)$$

Those offset energies are compiled in column 6 of Table 2. For example, in the case of  $\text{Tb}^{3+}$  the quenching energy barrier added to the  ${}^5D_4$

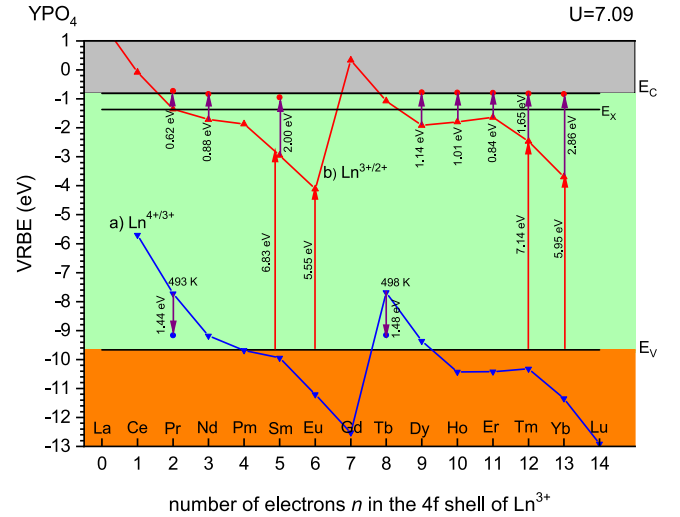


Fig. 5. The room temperature vacuum referred binding energy scheme for the trivalent and divalent  $4f^n$  lanthanide ground state levels in  $\text{YPO}_4$ . (a) Connects the VRBE in the  $\text{Ln}^{3+}$   $4f^n$  ground state levels and can also be denoted as the  $\text{Ln}^{4+/3+}$  charge transition levels, (b) connects the same for divalent lanthanides.  $E_V$ ,  $E_X$ ,  $E_C$  are the VRBE at the valence band top, in the host exciton state, and at the conduction band bottom, respectively. Observed energies for VB  $\rightarrow$   $\text{Ln}^{3+}$  CT, electron trap depths, and hole trap depths are written along the drawn arrows. The endpoints are indicated by solid bullet data symbols near  $E_C$  and  $E_V$ .

level location in the band gap leads on average to an energy of about  $\Delta E_{\text{offset}} = (0.5 \pm 0.15)$  eV below  $E_C$ . These values will be used in the discussion section to assess the accuracy and systematic errors in VRBE diagrams.

When thermal quenching of lanthanide luminescence involves the thermally excited electron or hole transfer from an excited lanthanide state to a host band, the physical processes are similar as with thermoluminescence when an electron or hole is thermally excited from the lanthanide ground state to the host band. Fig. 5 shows the room temperature VRBE diagram for the lanthanides in  $\text{YPO}_4$  as constructed with the RCS-model [10,16,17]. It shows that the ground states of the divalent lanthanides  $\text{Pr}^{2+}$  until  $\text{Yb}^{2+}$  are 0.5 to 3.0 eV below the CB-bottom which means that the corresponding trivalent lanthanides form 0.5 to 3.0 eV deep electron traps. Similarly, the ground state of  $\text{Ce}^{3+}$ ,  $\text{Pr}^{3+}$ , and  $\text{Tb}^{3+}$  are several eV above the VB-top and they form stable traps for holes generated in the VB. One may then combine a deep hole trap like  $\text{Ce}^{3+}$  with a shallower electron trap like  $\text{Pr}^{3+}$  until  $\text{Yb}^{3+}$  to systematically study electron release from  $\text{Ln}^{2+}$  with TL techniques. First studies were performed in 2008 by Bos et al. [24], and several studies on this system followed [25–27]. Fig. 6 shows the sequence of TL glow curves for  $\text{YPO}_4:\text{Ce}^{3+};\text{Ln}^{3+}$  from data in [26]. First the phosphor was charged by  $\beta$ -irradiation creating holes in the VB that are trapped to form  $\text{Ce}^{4+}$  and creating electrons in the CB that are trapped to form divalent lanthanides. Next the phosphor is heated linearly with time at a rate of  $\beta = 0.1$  K/s. The TL intensity  $I(T)$  from  $\text{Ce}^{3+}$   $5d\text{-}4f$  emission shows typical glow curves with initially an exponential rise, followed by the maximum at temperature  $T_m$  and then dropping rapidly towards zero. One may also replace  $\text{Ce}^{3+}$  for another hole trap like  $\text{Pr}^{3+}$  or  $\text{Tb}^{3+}$  to obtain the same sequence of glow peaks but then with recombination luminescence from  $\text{Pr}^{3+}$  or  $\text{Tb}^{3+}$  [26,27].

Solving the rate equations describing the thermally activated release of a charge carrier from a trap of depth  $\Delta E_t$  when a sample is heated at a linear rate of  $\beta$  K/s one obtains, assuming first order recombination kinetics, the Randall-Wilkins equation for the TL intensity  $I(T)$  as function of temperature [6–8],

$$I(T) = n_0 \frac{s}{\beta} \exp\left(-\frac{\Delta E_t}{kT}\right) \exp\left[-\frac{s}{\beta} \int_{T_0}^T \exp\left(-\frac{\Delta E_t}{kT'}\right) dT'\right] \quad (12)$$

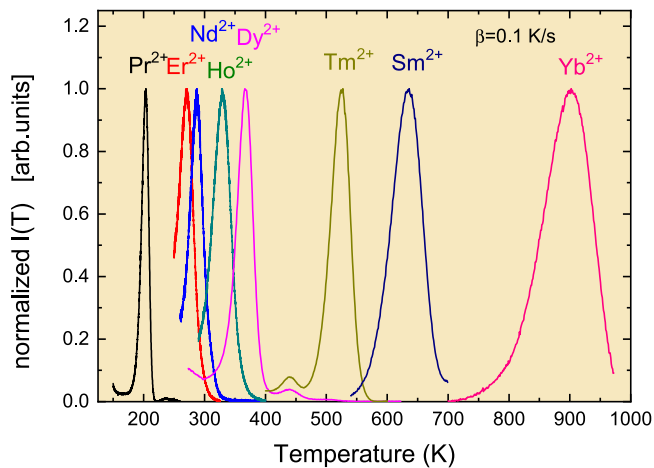


Fig. 6. The TL glow curves for  $\text{YPO}_4:\text{Ce}^{3+};\text{Ln}^{3+}$  phosphors at heating rate  $\beta = 0.1$  K/s as measured in [26].

where  $n_0$  the number of traps that were filled during the preceding charging phase,  $s$  is the same as  $I_0$  that appears in the Arrhenius equation Eq. (9), and  $k$  the Boltzmann constant. The first exponential describes the exponential rise of the glow peak, and the second exponential the rapid drop towards zero. From Eq. (12) one may derive a relation for the temperature  $T_m$  at the maximum of the glow peak

$$\frac{\beta \Delta E_t}{k T_m^2} = s \exp\left(-\frac{\Delta E_t}{k T_m}\right) \quad (13)$$

with the materials parameter  $s$  and  $\Delta E_t$ .

Using simple models,  $s$  can be related to the maximum phonon frequency  $\nu_0$ , a transition probability  $\kappa$  to the delocalized state, and a term that contains the entropy change  $\Delta S$  upon delocalizing the charge carrier [8],

$$s = \nu_0 \kappa \exp\left(\frac{-\Delta S}{k}\right). \quad (14)$$

Problem is that we do not know how to evaluate  $\kappa$  and  $\Delta S$ . Besides, we do not know to what extent Eq. (14) really applies and alternative theories are still being developed [28]. In this work we will simply assume that  $s = \nu_0$  which depending on the compound ranges from  $4 \times 10^{12}$  Hz to  $4 \times 10^{13}$  Hz [29]. Note that the precise value for  $s$  is not essential since a factor of 100 difference only results in a 0.05 eV different trap depth evaluated with Eq. (13).

Fig. 7 shows how  $T_m$  changes with  $\Delta E_t$  for various values of  $G \equiv \log(s/\beta)$  where  $\beta$  in TL recordings falls usually between 0.05 K/s and 5 K/s. Almost perfect proportional relations emerge with proportionality constants from 300 K/eV to 400 K/eV. The data points in Fig. 7 are from the results of  $\text{YPO}_4:\text{Ce}^{3+};\text{Ln}^{3+}$  in Fig. 6. Assuming  $s = 4 \times 10^{13}$  Hz or  $G = 14.6$  when  $\beta = 0.1$  K/s, the  $\Delta E_t$  were derived from the  $T_m$  values using Eq. (13). A linear fit through the data provides a slope of 314 K/eV with an intercept at 11.4 K for  $\Delta E_t = 0$ . The intercept demonstrates that for very small  $\Delta E_t$ ,  $T_m$  is not strictly proportional to  $\Delta E_t$  anymore. The 314 K/eV result for  $\text{YPO}_4$  is also listed in the last row of Table 2 to demonstrate similarity with thermal quenching. The value of 314 K/eV would also have been obtained in the case of luminescence quenching when  $\tau_v \approx 550$  s. Translated to a TL-recording this is the typical time needed to record a TL-glow of about 55 K width at a heating rate of 0.1 K/s.

The problem with using Eq. (12) is that in practice the trap depth  $\Delta E_t$  will not be single valued but there will be a trap depth distribution around an average, just like with the Arrhenius equation to describe thermal quenching of luminescence. Examples can be found in [30–33]. Likewise, there is not much point in fitting a TL-glow peak with the idealized first order RW-equation. One may exploit methods and

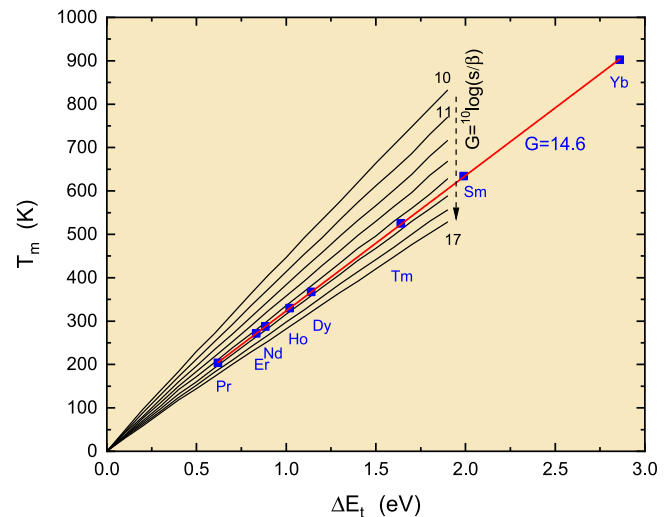


Fig. 7. The temperature  $T_m$  as function of  $\Delta E_t$  derived from the Randall-Wilkins equation for values  $G = \log(s/\beta)$  ranging 10, 11, 12, .. to 17. The data symbols refer to results from TL-glow peaks of  $\text{YPO}_4:\text{Ce}^{3+};\text{Ln}^{3+}$  for  $G = 14.6$ .

techniques like the initial rise method, peak cleaning techniques and variable heating rate plot to extract information from TL [8,24]. In this work we will follow a more practical route. In the presence of a distribution of  $\Delta E_t$  or other than first order recombination kinetics, the shape of the TL-glow will broaden. Fortunately, Eq. (13) appears to hold also quite well when  $\Delta E_t$  is interpreted as the average trap depth [34]. Because  $T_m$  varies proportionally with  $\Delta E_t$  and the TL-glow peak is apart from the exponential rise reasonably symmetric, the temperature  $T_m$  does not change dramatically in the presence of a distribution. The glow peak will just broaden. Again this is quite similar as with the  $T_{50}$  value from the thermal quenching curve of luminescence. Given the heating rate  $\beta$  together with a reasonable estimate for  $s$ , one may then directly obtain  $\Delta E_t$  from the observed value of  $T_m$ . This is the method that will be followed throughout this work.

The  $\Delta E_t$  derived from the observed  $T_m$  in Fig. 6 should correlate with the energy difference between the CB-bottom of  $\text{YPO}_4$  and the  $\text{Ln}^{3+/2+}$  CTL. The obtained e-trap depths are shown in Fig. 5 with the vertical arrows starting at the  $\text{Ln}^{3+/2+}$  CTL. Apart from  $\text{Sm}^{2+}$  they all end within 0.1 eV from the CB-bottom at  $E_C = -0.81$  eV. Note that the  $T_m$  values range from 200 K to 900 K, and over such 700 K temperature range the VRBE energy at the CB-bottom and of the  $\text{Ln}^{3+/2+}$  CTL will change. This aspect was further treated in [23] where it was concluded that the CB-bottom and the  $\text{Ln}^{3+/2+}$  CTL shift in the same direction when temperature changes thus not affecting the e-trap depth too much. This is now reconfirmed with the results in Fig. 5. In the Results section below, we will collect TL-data from the archival literature to derive the electron and hole trapping depths of lanthanides. For each compound the room temperature VRBE diagram will be constructed, and the experimental trapping depths will be compared with what the VRBE scheme predicts. The aim is to prove, on the one hand, the consistency between experiment and prediction and, on the other hand, to unveil systematic errors or shortcomings in VRBE diagram construction.

### 3. Results

A general problem with TL-curves is how to assign an observed TL-glow peak to a specific electron releasing or hole releasing defect. There are always trapping centres in a compound of which the nature and the location of their CTLs are not known beforehand. Even in the case of intentionally doped materials often the location of the CTLs of the dopants are not known. How then to decide which glow peak belongs to

**Table 3**

The parameters used for room temperature VRBE diagram construction where compounds are arranged in sequence of decreasing  $U$ -value together with the obtained  $E_V$  and  $E_C$  values. All energies are in eV. The errors in  $U$ ,  $E^{CT}(Eu^{3+})$ , and  $E^{ex}$  are estimated typically  $\pm 0.1$  eV.

A	$U$	$E^{CT}$	$E_V$	$E^{ex}$	$E_C$	$\beta(2+)$	$\beta(3+)$	$f(2+)$	$f(3+)$
free Ln	18.05		–		–	1.000	1.000	0.000	0.000
NaLaF <sub>4</sub>	7.51	7.72	–12.05	10.28	–0.92	0.956	0.956	0.582	0.425
LaPO <sub>4</sub>	7.18	4.84	–9.00	7.95	–0.54	0.943	0.943	0.582	0.425
NaYP <sub>2</sub> O <sub>7</sub>	7.18	5.46	–9.62	7.82	–1.31	0.943	0.943	0.582	0.425
GdPO <sub>4</sub>	7.13	5.15	–9.28	8.00	–0.77	0.941	0.941	0.582	0.425
YPO <sub>4</sub>	7.09	5.55	–9.66	8.30	–0.81	0.950	0.940	0.630	0.425
LuPO <sub>4</sub>	7.08	5.65	–9.76	8.55	–0.62	0.939	0.939	0.617	0.425
Sr <sub>2</sub> MgSi <sub>2</sub> O <sub>7</sub>	7.03	4.56	–8.64	7.20	–1.03	0.937	0.937	0.582	0.425
MgGeO <sub>3</sub>	7.00	4.75	–8.82	5.93	–2.61	0.950	0.936	0.651	0.425
LiLuGeO <sub>4</sub>	6.95	5.21	–9.25	6.25	–2.69	0.934	0.934	0.582	0.425
NaLuGeO <sub>4</sub>	6.95	5.35	–9.39	6.33	–2.74	0.934	0.934	0.582	0.425
NaYGeO <sub>4</sub>	6.94	5.33	–9.37	6.23	–2.83	0.934	0.934	0.582	0.425
Ca <sub>2</sub> MgSi <sub>2</sub> O <sub>7</sub>	6.91	4.56	–8.58	7.00	–1.19	0.950	0.934	0.617	0.425
LiScGeO <sub>4</sub>	6.90	5.56	–9.58	6.40	–2.85	0.932	0.932	0.582	0.425
LiLuSiO <sub>4</sub>	6.90	5.37	–9.39	7.30	–1.66	0.940	0.932	0.651	0.425
Gd <sub>3</sub> Ga <sub>5</sub> O <sub>12</sub>	6.90	5.02	–9.04	5.70	–3.08	0.932	0.932	0.582	0.425
LiYSiO <sub>4</sub>	6.89	5.32	–9.33	7.40	–1.49	0.950	0.932	0.685	0.425
Ca <sub>3</sub> Si <sub>2</sub> O <sub>7</sub>	6.88	5.10	–9.11	6.78	–1.96	0.940	0.931	0.617	0.425
Gd <sub>3</sub> AlGa <sub>4</sub> O <sub>12</sub>	6.88	5.00	–9.01	5.97	–2.75	0.931	0.931	0.617	0.425
Gd <sub>3</sub> Al <sub>2</sub> Ga <sub>3</sub> O <sub>12</sub>	6.86	5.20	–9.20	6.08	–2.82	0.930	0.930	0.617	0.425
Lu <sub>3</sub> Al <sub>2</sub> Ga <sub>3</sub> O <sub>12</sub>	6.85	5.40	–9.39	6.50	–2.56	0.940	0.930	0.617	0.425
Gd <sub>3</sub> Sc <sub>2</sub> Ga <sub>3</sub> O <sub>12</sub>	6.84	4.77	–8.76	6.00	–2.47	0.930	0.930	0.617	0.425
Y <sub>3</sub> Al <sub>2</sub> Ga <sub>3</sub> O <sub>12</sub>	6.80	5.19	–9.16	6.33	–2.51	0.940	0.928	0.617	0.425
Y <sub>3</sub> Al <sub>5</sub> O <sub>12</sub>	6.77	5.45	–9.40	6.85	–2.18	0.940	0.927	0.616	0.425
LaAlO <sub>3</sub>	6.76	3.90	–7.85	5.95	–1.62	0.926	0.926	0.582	0.425
GdAlO <sub>3</sub>	6.75	4.75	–8.69	7.30	–0.97	0.930	0.926	0.685	0.425
Sr <sub>3</sub> SiO <sub>5</sub>	6.74	3.76	–7.70	6.15	–1.25	0.940	0.926	0.651	0.425
SrSi <sub>2</sub> O <sub>2</sub> N <sub>2</sub>	6.70	3.38	–7.30	6.20	–0.79	0.924	0.924	0.685	0.425
LiTaO <sub>3</sub>	6.70	4.57	–8.49	5.44	–2.81	0.922	0.922	0.617	0.425
MgO	6.60	5.27	–9.14	7.54	–1.15	0.920	0.920	0.582	0.425
YSiO <sub>2</sub> N	6.60	3.80	–7.67	5.90	–1.49	0.924	0.924	0.617	0.425
SrSi <sub>2</sub> AlO <sub>2</sub> N <sub>3</sub>	6.60	2.85	–6.72	5.44	–1.05	0.925	0.920	0.685	0.425
Lu <sub>2</sub> O <sub>2</sub> S	6.40	3.72	–7.50	4.63	–2.70	0.912	0.912	0.582	0.425
Y <sub>2</sub> O <sub>2</sub> S	6.37	3.76	–7.53	4.68	–2.67	0.911	0.911	0.582	0.445
Gd <sub>2</sub> O <sub>2</sub> S	6.35	3.72	–7.48	4.68	–2.62	0.910	0.910	0.582	0.445
Ca <sub>2</sub> Si <sub>3</sub> N <sub>8</sub>	6.35	2.98	–6.74	5.05	–1.48	0.930	0.930	0.719	0.445
La <sub>2</sub> O <sub>2</sub> S	6.30	3.64	–7.37	4.61	–2.59	0.908	0.915	0.582	0.445
Ln-metal	5.70		–		–	0.910	0.910	0.680	0.680

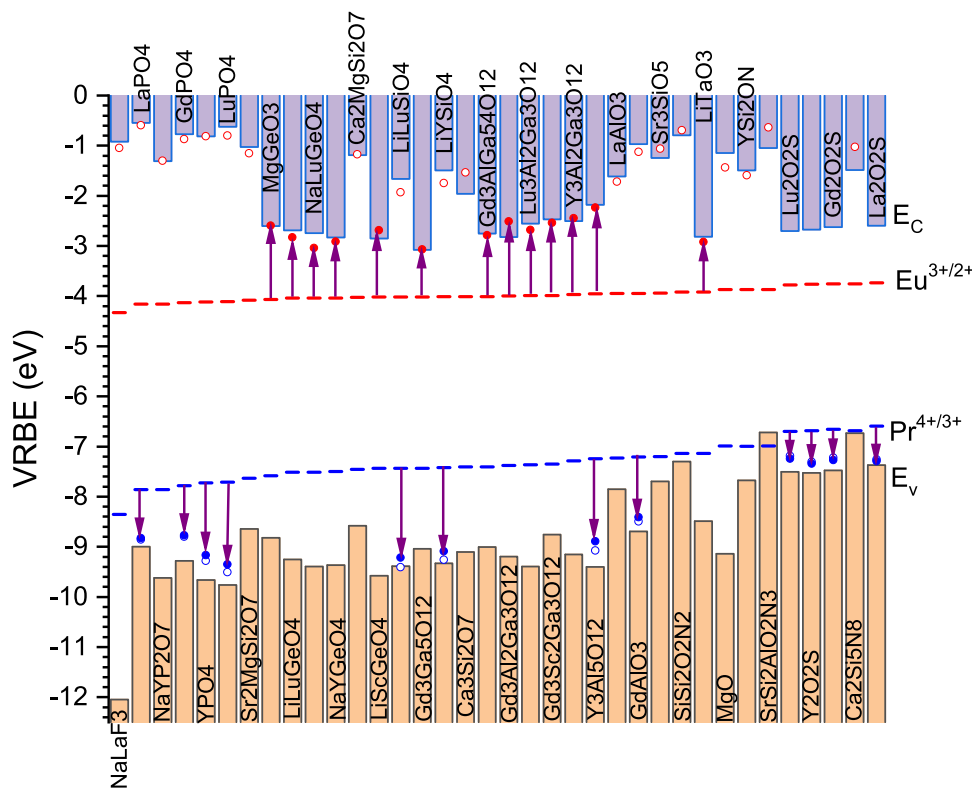
a lanthanide and which to a defect, and whether it is from hole release or from electron release? Since the invent of HRBE and VRBE schemes involving the lanthanides, we have a means to establish the location of the lanthanide CTLs. However, accuracy is limited to several 0.1 eV and knowing that the  $T_m$  of glow peaks may shift by 30–40 K/0.1 eV, this still makes assignment of TL-glow peaks to specific lanthanide trapping centres not trivial. Matters became manageable when combining TL studies on various combinations of lanthanides with HRBE and VRBE schemes as in Fig. 5. We learned from such schemes that the  $Ce^{4+/3+}$  CTL in wide bandgap compounds is always several eV above the VB-top making  $Ce^{4+}$  a stable hole trap. When combining  $Ce^{3+}$  with a  $Ln^{3+}$  as in Fig. 6 one observes with TL studies  $Ce^{3+}$  emission which implies that the  $Ln^{3+}$  acted as an electron trap and the glow is from e-release with recombination at  $Ce^{4+}$ . One may also combine the hole trap  $Pr^{3+}$  with the deeper electron trap of  $Eu^{3+}$ . In such case with TL studies the hole is released from  $Pr^{4+}$  to recombine with  $Eu^{2+}$  resulting in  $Eu^{3+}$  emission. Thus by studying different combinations of lanthanides in the same compound one may eventually evidence that an observed glow peak is from e-release or h-release and assign it to a specific lanthanide dopant.

Since the work on YPO<sub>4</sub>, many other compounds with lanthanides were studied by TL. These data have been collected and re-analysed

to derive the trapping energies. In total information from 36 different lanthanide doped compounds were found. For each compound information on the energies  $E^{ex}$  and  $E^{CT}(Ln^{3+})$  was gathered from published spectroscopic data. In each case the values that apply at room temperature were used. In cases that only information at e.g. 10 K was available, a correction to RT was made using the methods in [23] and Eq. (8) for  $E^{CT}(T)$ . For the exciton binding energy, the last term of Eq. (7) was used. The  $U$ -value was obtained with the methods outlined in [35]. When the centroid shift of the  $Ce^{3+}$  4f-5d transitions is known, as for YPO<sub>4</sub>, the  $U$ -value was derived from that centroid shift and will be denoted as  $U_c$ . In cases when the compound contains only one type of anion, the estimator tool based on the average cation electronegativity  $\chi_{av}$  of the compound in [35] was used. Such  $U$ -value will be denoted as  $U_X$ . For the compounds with two types of anions the method of a weighted average of single anion compounds was followed [35] and denoted as  $U_w$ . All parameters used for constructing the VRBE diagrams are compiled in Table 3 along with the energies  $E_V$  and  $E_C$  obtained with Eqs. (6) and (7).

The VRBE diagram for each compound in the same style as the one for YPO<sub>4</sub> in Fig. 5 can be found in Fig. SI-3 until Fig. SI-14. Fig. 8 shows a stacked VRBE diagram of the 36 compounds in Table 3 together





**Fig. 8.** Stacked VRBE diagram with the  $\text{Eu}^{3+/2+}$  and  $\text{Pr}^{4+/3+}$  CTLs of the 36 compounds of this study. Upward pointing arrows starting at the  $\text{Eu}^{3+/2+}$  CTLs have length equal to the  $\text{Eu}^{2+}$  e-trap depths. The solid bullet data points are the endpoint energies. The open bullet data points near  $E_C$  mark the average endpoint energies derived from e-trap depths from divalent lanthanides other than  $\text{Eu}^{2+}$ . Downward pointing arrows starting at the  $\text{Pr}^{4+/3+}$  CTLs have length equal to the  $\text{Pr}^{4+}$  h-trap depths at temperature  $T_m$ . The solid bullet data points are the endpoint energies. The open bullet data points near  $E_V$  are the endpoint energies when a correction to RT is made.

with the CTLs of  $\text{Pr}^{4+/3+}$  and  $\text{Eu}^{3+/2+}$ . Compounds are arranged in sequence of decreasing  $U$ -value and therefore increasing chemical shift and increasing energy of the CTLs.

### 3.1. Lanthanide electron trapping depths

**Table 4** compiles the compounds and references where TL-curves with glow peaks due to release of an electron from a divalent lanthanide was reported. The temperatures  $T_m$  at the maxima of the observed glow peak together with the used TL heating rate  $\beta$  and the used hole trapping and recombination centre can be found in Table SI-I. Using Eq. (13), the e-trap depth  $\Delta E_t^e$  was derived from  $T_m$ ,  $\beta$  and the value for  $s$ . The obtained values for  $\Delta E_t^e$  together with the used  $s$  are compiled in **Table 4**. Here, one should regard  $\Delta E_t^e$  as a measure for the average value of an unknown trap depth distribution.

Depending on the location of the  $\text{Ln}^{3+/2+}$  CTL curve with respect to the energy  $E_C$  at the CB-bottom different trivalent lanthanides may act as an electron trap. For the compound  $\text{YPO}_4$  we have information on the e-trap depths of 8 different lanthanides. The glow peaks were shown in **Fig. 6** and the e-trap depth values in **Table 4** were used in **Fig. 7**. **Fig. 5** shows that the CTLs for  $\text{La}^{3+/2+}$ ,  $\text{Ce}^{3+/2+}$  and  $\text{Gd}^{3+/2+}$  are inside the CB and those lanthanides are not able to trap an electron in the 4f-orbital. Here we have to note that the ground state electron configuration for these divalent lanthanides will be  $4f^{n-1}5d$  and not  $4f^{n+1}$ , and the genuine CTLs will be at lower energy. The  $\text{Eu}^{3+/2+}$  CTL is very deep below the CB-bottom and a TL-glow peak from the  $\text{Eu}^{2+}$  e-trap would be located well above 1000 K and beyond the range of TL-readers.  $\text{Eu}^{2+}$  e-trap depths are only available on compounds, with a low lying CB-bottom. The stacked diagram of **Fig. 8** shows that in seven garnet compounds, five germanate compounds, and in  $\text{LiTaO}_3$ , the CB-bottom is in the range  $-2.2$  eV to  $-3.2$  eV. Those are the compounds in **Table 4** where glow peaks have been attributed to the  $\text{Eu}^{2+}$  and  $\text{Yb}^{2+}$  e-traps. The

VRBE diagrams of those compounds in **Fig. SI-3** until **Fig. SI-14** show that the  $\text{Ln}^{3+/2+}$  CTLs of all other lanthanide are well inside the CB and electron trapping is not possible. For  $\text{SrSi}_2\text{O}_2\text{N}_2$  two sets of e-trap values are listed in **Table 4** for the lanthanides Dy, Ho, and Er. For each lanthanide, the TL-curve shows a strong glow peak accompanied by a weak satellite glow peak at higher temperature [58], see also Table SI-I. Apparently, there are two sites for the lanthanides with differing e-trap depths. The ones responsible for the satellite glow peaks have 0.14 eV deeper e-traps. In **Fig. SI-11c**, we suggest that the two sites differ in the  $\text{Ln}^{3+/2+}$  CTL energies. Similar applies for  $\text{Ca}_3\text{Si}_2\text{O}_7$  where Ueda et al. [49] observe double e-release glow peaks for  $\text{Sm}^{2+}$  and  $\text{Tm}^{2+}$ . **Table 4** and **Fig. SI-8b** show that they differ about 0.23 eV in energy. One may interpret this as site dependent  $\text{Ln}^{3+/2+}$  CTL energies. However, it is also possible that a fraction of the e-trap defects is close neighbour to the h-trap defects. Coulomb attraction between trapped electron and trapped hole combined with local lattice distortions may facilitate the TL-recombination leading to lower e-trap depths.

### 3.2. Lanthanide hole trapping depths

The VRBE scheme for the wide bandgap compound  $\text{YPO}_4$  in **Fig. 5** shows that only  $\text{Ce}^{3+}$ ,  $\text{Pr}^{3+}$ , and  $\text{Tb}^{3+}$  are deep hole trapping centres and this applies for most oxide based compounds. A TL glow peak has never been assigned to hole release from  $\text{Ce}^{4+}$  in an oxide compound. The trap is just too deep to generate a glow peak below say 1000 K. Only hole release from  $\text{Pr}^{4+}$  and  $\text{Tb}^{4+}$  has been reported. The used heating rates  $\beta$  and observed glow peak maxima  $T_m$  together with the used electron trapping and recombination centre can be found in Table SI-II. **Table 5** compiles the h-trap depths of  $\text{Pr}^{4+}$  and  $\text{Tb}^{4+}$  derived from  $T_m$  using the value for  $\beta$  and the listed frequency factors  $s$ .

For the oxide compounds in **Table 5**, the h-trap depths  $\Delta E_t^h$  for  $\text{Pr}^{4+}$  and  $\text{Tb}^{4+}$  appear in the range 0.6 to 1.8 eV. In the four oxysulfide

**Table 4**

The depth  $\Delta E_e^c$  of the electron trap in eV on a divalent lanthanide in compounds as derived from the temperature  $T_m$  at the maximum of the glow peak. The used frequency factor  $s$  is in units of  $10^{13}$  Hz.

A	$s$	Pr <sup>2+</sup>	Nd <sup>2+</sup>	Sm <sup>2+</sup>	Eu <sup>2+</sup>	Dy <sup>2+</sup>	Ho <sup>2+</sup>	Er <sup>2+</sup>	Tm <sup>2+</sup>	Yb <sup>2+</sup>	Ref.
NaLaF <sub>4</sub>	1.5			2					1.77		[36]
LaPO <sub>4</sub>	4		1.21	2.31		1.49	1.32	1.18	1.92		[37]
NaYP <sub>2</sub> O <sub>7</sub>	4			1.75		0.65	0.47				[38]
GdPO <sub>4</sub>	4						1.02				[37]
YPO <sub>4</sub>	4	0.62	0.88	2		1.14	1.01	0.84	1.65	2.86	[26]
LuPO <sub>4</sub>	4			2.07		1.18	1.03	1	1.71		[39]
Sr <sub>2</sub> MgSi <sub>2</sub> O <sub>7</sub>	2.5								1.4		[40]
MgGeO <sub>3</sub>	2.5				1.47					0.95	[41]
LiLuGeO <sub>4</sub>	2.5				1.21						[42]
NaLuGeO <sub>4</sub>	2.5				1						[43,44]
NaYGeO <sub>4</sub>	2.5				1.12						[43]
Ca <sub>2</sub> MgSi <sub>2</sub> O <sub>7</sub>	2.5			1.73					1.16		[45]
LiScGeO <sub>4</sub>	2.5				1.33						[42]
LiLuSiO <sub>4</sub>	2.5			1					0.4		[46]
Gd <sub>3</sub> Ga <sub>3</sub> O <sub>12</sub>	1.5				0.95						[47,48]
LiYSiO <sub>4</sub>	2.5			1.15					0.52		[46]
Ca <sub>3</sub> Si <sub>2</sub> O <sub>7</sub> (stronger)	2.85			1.12					0.62		[49]
Ca <sub>3</sub> Si <sub>2</sub> O <sub>7</sub> (weaker)	2.85			1.37					0.83		[49]
Gd <sub>3</sub> AlGa <sub>3</sub> O <sub>12</sub>	1.5				1.22						[47]
Gd <sub>3</sub> Al <sub>2</sub> Ga <sub>3</sub> O <sub>12</sub>	1.5				1.49						[47]
Lu <sub>3</sub> Al <sub>2</sub> Ga <sub>3</sub> O <sub>12</sub>	1.5				1.31					0.99	[50]
Gd <sub>3</sub> Sc <sub>2</sub> Ga <sub>3</sub> O <sub>12</sub>	1.5				1.45					≈0.99	[51]
Y <sub>3</sub> Al <sub>2</sub> Ga <sub>3</sub> O <sub>12</sub>	1.5				1.52					1.04	[52,53]
Y <sub>3</sub> Al <sub>5</sub> O <sub>12</sub>	1.7				1.72					1.31	[54]
LaAlO <sub>3</sub>	1.7			1.03					0.79		[55]
GdAlO <sub>3</sub>	1.7		0.45			0.69	0.54	0.4	1.17		[56]
Sr <sub>5</sub> SiO <sub>5</sub>	2.5			1.83					1.15		[57]
SrSi <sub>2</sub> O <sub>2</sub> N <sub>2</sub> (stronger)	2.5					1.13	0.99	0.85			[58]
SrSi <sub>2</sub> O <sub>2</sub> N <sub>2</sub> (weaker)	2.5					1.27	1.12	0.99			[58]
LiTaO <sub>3</sub>	2.5				1						[59]
MgO	1.5			1.23					0.93	2.03	[60,61]
YSiO <sub>2</sub> N	1.5			1.15					≈0.84		[33]
SrSi <sub>2</sub> AlO <sub>2</sub> N <sub>3</sub>	2.5		1.02			1.06	0.9	0.75	>1.71		[62]
Ca <sub>2</sub> Si <sub>5</sub> N <sub>8</sub>	2.5		0.45			0.52			1.03		[63,64]

**Table 5**

The depth  $\Delta E_h^c$  of the hole trap in eV on Pr<sup>4+</sup> and on Tb<sup>4+</sup> in compounds as derived from the temperature  $T_m$  at the maximum of the glow peak. The used frequency factor  $s$  is in units of  $10^{13}$  Hz.

A	$s$	Pr <sup>4+</sup>	Tb <sup>4+</sup>	Ref.
LaPO <sub>4</sub>	4	0.97	1.01	[37,65]
LaPO <sub>4</sub>	4	0.6	0.69	[37,65]
GdPO <sub>4</sub>	4	0.99	0.99	[65]
GdPO <sub>4</sub>	4	0.76	0.81	[65]
YPO <sub>4</sub>	4	1.44	1.48	[26,37]
LuPO <sub>4</sub>	4	1.64	1.68	[37]
LiLuSiO <sub>4</sub>	2.5	1.78	1.79	[46]
LiYSiO <sub>4</sub>	2.5	1.65	1.68	[46]
Y <sub>3</sub> Al <sub>5</sub> O <sub>12</sub>	1.7	1.65	1.61	[54,66]
GdAlO <sub>3</sub>	1.7	1.22	1.18	[56]
Lu <sub>2</sub> O <sub>2</sub> S	1.4	0.55	0.46	[67]
Y <sub>2</sub> O <sub>2</sub> S	1.3	0.66	0.6	[67]
Gd <sub>2</sub> O <sub>2</sub> S	1.3	0.62	0.56	[67]
La <sub>2</sub> O <sub>2</sub> S	1.1	0.7	0.68	[67]

compounds the trap depth is shallow and around 0.6 eV. This is due to the presence of the sulphide anion leading to a high VRBE at the VB-top as can be seen in the stacked diagram of Fig. 8. In the case of LaPO<sub>4</sub> and GdPO<sub>4</sub>, two sets of hole trap depths are listed in

**Table 5.** LaPO<sub>4</sub>:Pr<sup>3+</sup>;Eu<sup>3+</sup> and LaPO<sub>4</sub>:Tb<sup>3+</sup>;Eu<sup>3+</sup> were studied by Lyu and Dorenbos [37] and the TL-curves are reproduced in Fig. 9. Here Eu<sup>3+</sup> acts as the deep electron trap and Pr<sup>3+</sup> and Tb<sup>3+</sup> as the less deep hole traps. During TL-readout, the hole is released from Pr<sup>4+</sup> or Tb<sup>4+</sup> to recombine at Eu<sup>2+</sup> generating Eu<sup>3+</sup> emission. The glow peaks IIIa and IIIb were attributed to hole release from Tb<sup>4+</sup> and Pr<sup>4+</sup> and glow peaks IIa and IIb to hole release from unknown defects. In this work we also assign peaks IIa and IIb to hole release from Pr<sup>4+</sup> and Tb<sup>4+</sup> but at sites providing about 0.33 eV deeper h-traps than those responsible for glow peaks IIIa and IIIb. Similar situation exists for GdPO<sub>4</sub>, and the two sets of hole trap depths, differing about 0.2 eV, are listed in Table 5.

#### 4. Discussion

The results on e-trap depths and h-trap depths in Table 4 and 5 will be used three-fold. (1) We will analyse the relative variation in trap depth in going through the lanthanide series. That variation follows the shape of the zigzag lanthanide CTL-curves of Eq. (3). Because TL is a highly sensitive technique we will use the compiled data to critically analyse that shape and compound to compound variations therein. This analysis will provide information on the relaxation fractions  $f(Q, A)$  of relevance for the tilt parameters  $\alpha(Q, A)$  and will provide information on the nephelauxetic parameters  $\beta(Q, A)$ . (2) The trap depth expresses the location of the CTL with respect to the VB or CB of the host compound. We will focus on the e-trap depth of Eu<sup>2+</sup> as representative for the Ln<sup>3+/2+</sup> CTL-curve, and on the h-trap depth of

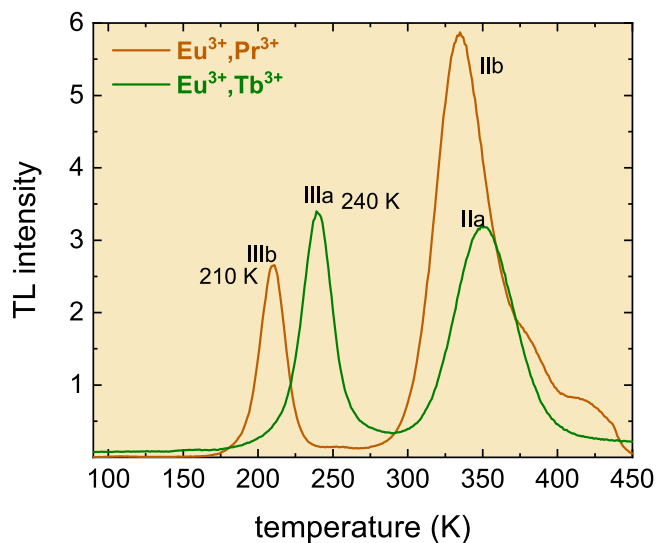


Fig. 9. The TL glow curves for  $\text{LaPO}_4:\text{Pr}^{3+};\text{Eu}^{3+}$  and  $\text{LaPO}_4:\text{Tb}^{3+};\text{Eu}^{3+}$  monitoring  $\text{Eu}^{3+}$  emission at a heating rate  $\beta = 1$  K/s as measured in [37].

$\text{Pr}^{4+}$  as representative for the  $\text{Ln}^{4+/3+}$  CTL-curve. Ideally the e-trap depth added to the  $\text{Eu}^{3+/2+}$  CTL should coincide with the CB-bottom and similarly the h-trap depth subtracted from the  $\text{Pr}^{4+/3+}$  CTL should coincide with the VB-top. This analysis will provide insight in the consistency between the parameters  $U$ ,  $E^{ex}$ , and  $E^{CT}$  with observed trapping depths. (3) With TL-studies, the thermally excited release of charge carriers from the lanthanide ground states are probed. With studies on thermal quenching of lanthanide emission, the thermally excited release of charge carriers from excited states are probed. Both should be consistent with each other and with the VRBE diagram.

#### 4.1. The shape of the $\text{Ln}^{3+/2+}$ and $\text{Ln}^{4+/3+}$ CTL-curves

In the RCS-model, the shape of the lanthanide CTL curves is given by Eq. (3). It is foremost based on the free lanthanide ion CTL curves as shown in Fig. 2. These curves are being tilted when in compounds as shown in Fig. 4. The relaxation fractions  $f(Q, A)$  provide the tilt parameters  $\alpha(Q, A)$  in Eq. (5) which is then used in Eq. (3). In addition we have the nephelauxetic parameters  $\beta(Q, A)$  which causes a lowering of the right hand branch with several 0.1 eV as demonstrated in Fig. 2. By definition  $\beta = 1$  for the free lanthanides and it may reduce to values around 0.91 for highly covalent compounds like the selenides. As first approximation Eq. (4) will be used to estimate  $\beta$ . Next, one may change the values slightly to attain best agreement between the  $\text{Ln}^{Q+1/Q}$  CTL shapes and the observed trap depths. For the relaxation fractions, we start as first approximation with  $f(2+) = 0.63$  and  $f(3+) = 0.425$ . Again values can be slightly modified to attain best agreement between the  $\text{Ln}^{Q+1/Q}$  CTL shapes and the observed trap depths. The chosen set of values for each compound can be found in Table 3.

$\text{YPO}_4$  is the compound with most information on e-trap depths for different lanthanides. Only then it is feasible to deduce a unique set of  $\beta(2+)$  and  $f(2+)$  values. However, in most cases we know e-trap depths of only one or two lanthanides, and then it becomes difficult or impossible to find a unique combination. We then tend to choose values close to the starting values. Fig. 10 shows the chosen values for  $\beta(2+)$  in Table 3 where the dashed line is given by Eq. (4). Often the values for  $\beta(3+)$  were chosen equal to that for  $\beta(2+)$ .

There are 5 compounds in Table 4 where we can compare the e-trap depth of  $\text{Dy}^{2+}$  from the right hand branch of the CTL curve with that of  $\text{Nd}^{2+}$  from the left hand branch. With decrease of  $U$ -value,  $\beta(2+)$  tends to decrease and the right hand branch will lower with respect to the left hand branch. This predicts that the  $\text{Dy}^{2+}$  to  $\text{Nd}^{2+}$  trap depth difference

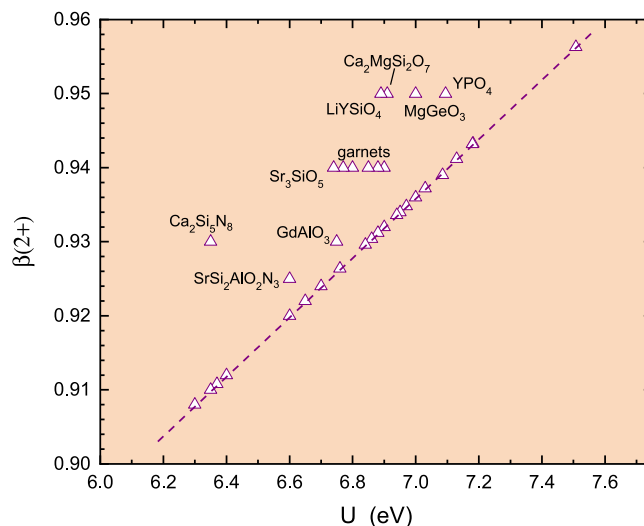


Fig. 10. Values for  $\beta(2+)$  used to construct the VRBE schemes.

should increase. However, the opposite appears to be the case. It is 0.28 eV, 0.26 eV, 0.24 eV, 0.04 eV, and 0.07 eV for  $\text{LaPO}_4$ ,  $\text{YPO}_4$ ,  $\text{GdAlO}_3$ ,  $\text{SrSi}_2\text{AlO}_2\text{N}_3$ , and  $\text{Ca}_2\text{Si}_3\text{N}_8$ . With decrease of the  $U$ -value, the chemical shift increases and with Eq. (5) the tilt parameter  $\alpha(2+)$  tends to increase, and that will have an opposite effect on the  $\text{Dy}^{2+}$  to  $\text{Nd}^{2+}$  trap depth difference. It seems then that, the parameter  $\alpha(2+)$  is more important for the energy differences than the parameters  $\beta$ .

TL data on hole release from  $\text{Pr}^{4+}$  from the left hand branch and  $\text{Tb}^{4+}$  from the right hand branch in 8 different compounds were already presented and analysed in [17]. Table 5 reproduces the same 8 compounds plus in addition recent data on the  $\text{RE}_2\text{O}_2\text{S}$  ( $\text{RE} = \text{La}, \text{Gd}, \text{Y}, \text{Lu}$ ) from [67]. A trend is observed with decrease of  $U$ -value in the h-trap depth differences between  $\text{Pr}^{4+}$  and  $\text{Tb}^{4+}$ .  $\text{Tb}^{4+}$  appears a 0.04–0.09 eV deeper h-trap than  $\text{Pr}^{4+}$  in  $\text{LaPO}_4$  but in the  $\text{RE}_2\text{O}_2\text{S}$  it is 0.02–0.09 eV more shallow. Apparently when  $U$  decreases from 7.2 to 6.3 eV, the  $\text{Tb}^{4+/3+}$  CTL moves down by  $\approx 0.15$  eV with respect to that of  $\text{Pr}^{4+/3+}$ . Values for  $\beta(3+)$  and  $f(3+)$  listed for the compounds in Table 5 were chosen such that the h-trap depth difference between  $\text{Pr}^{4+}$  and  $\text{Tb}^{4+}$  agrees within 0.02 eV with experiment. Apart from  $\text{La}_2\text{O}_2\text{S}$ , we used Eq. (4) to choose  $\beta(3+)$ .  $f(3+)$  was kept at 0.425 as much as possible. Only for three oxysulphides we needed to choose a somewhat larger value of 0.445.

The observation that the  $f$  and  $\beta$  values remain always fairly close to the starting estimated values implies that generally the trap depths closely follow the CTL shapes from the RCS-model. However, we also have to conclude that they still may deviate 0.1–0.2 eV. A likely reason is uncertainty in the value for  $f(Q, A)$  that determines the tilt factor  $\alpha(Q, A)$  in Eq. (5). The amount of lattice relaxation around a lanthanide dopant on a site in a compound is usually not known and can/will differ from compound to compound. Furthermore, introducing  $f(Q, A)$  was under the assumption that each bondlength from a lanthanide to its neighbouring anion changes with the same fraction (breathing mode type of relaxation), and also that those fractions are the same for each lanthanide. Both are not necessarily true. It is well possible that one coordinating anion relaxes much more than others. It all depends on crystal structure and bonding. One may even imagine that  $f(Q, A)$  for the larger lanthanides at the beginning of the lanthanide series has different value than at the end of the series. Such dependence would distort the CTL curves beyond what can be accounted for with Eq. (3). It will be clear that we are then hitting the limits of our VRBE construction methods. In addition, we have seen for  $\text{Ca}_3\text{Si}_2\text{O}_7$  and  $\text{SrSi}_2\text{O}_2\text{N}_2$  the presence of two different sites with different e-trap depths and similar for  $\text{LaPO}_4$  and  $\text{GdPO}_4$  with different h-trap depths.

In each VRBE diagram of Fig. SI-3 until Fig. SI-14 and also for  $\text{YPO}_4$  in Fig. 5, the e-trap depth added to the  $\text{Ln}^{3+/2+}$  CTL energy is indicated by a data symbol. We will call that the endpoint energy. The same is done for the h-trap depths subtracted from the  $\text{Ln}^{4+/3+}$  CTLs. Ideally the endpoint energies for different lanthanides in the same compound should have the same energy. For  $\text{YPO}_4$  in Fig. 5 this is very nicely confirmed but also for most of the other compounds in Fig. SI-3 until Fig. SI-14. This all confirms that the TL trap depths follow very nicely the shape of the  $\text{Ln}^{Q+1/Q}$  CTL curves. Some endpoint energies may deviate as for  $\text{Sm}^{2+}$  in  $\text{NaYP}_2\text{O}_7$  (see Fig. SI-3c) and  $\text{Sr}_3\text{SiO}_5$  (see Fig. SI-11b),  $\text{Tm}^{2+}$  in  $\text{LiLuSiO}_4$  (see Fig. SI-7b) and  $\text{LiYSiO}_4$  (see Fig. SI-8a), and  $\text{Yb}^{2+}$  in  $\text{Gd}_3\text{Sc}_2\text{Ga}_3\text{O}_{12}$  (see Fig. SI-9c). Deviations are then 0.1–0.4 eV large, but for all other cases the endpoint energies are all within 0.1 eV from each other. We regard this as a confirmation and as evidence that Eq. (3) from the RCS-model provides a correct description of the  $\text{Ln}^{Q+1/Q}$  CTL curves. The assumption that the relaxation fractions  $f(Q, A)$  for a compound are the same for each lanthanide and for each lanthanide-ligand bond is not necessarily correct. Since we do not have the means to establish those fractions for an individual compound, the assumption leads to an unavoidable error source in CTL energies of the order of several 0.1 eV. This entails then a fundamental contribution to the errors in VRBE diagram construction.

#### 4.2. Comparing TL trap-depth and VRBE trap depth

The shapes of CTL curves together with its limitations and errors are quite well established and validated. Next step is to assess its location with respect to the host bands and the vacuum level. For that, we will use the e-trap depth data for  $\text{Eu}^{2+}$  and the hole trap depth data for  $\text{Pr}^{3+}$  both from the left hand branch of the CTL-curves. Ideally,

$$E_V + E^{CT}(\text{Eu}^{3+}, RT) + \Delta E_i^e(\text{Eu}^{2+}) = E_C \quad (15)$$

and

$$E_V + E^{CT}(\text{Eu}^{3+}, RT) - U + (5.50 - 1.51 \times \beta(3+) + 6.05 \times \alpha(3+)) - \Delta E_i^h(\text{Pr}^{4+}) = E_V \quad (16)$$

where in the latter equation the term between the braces is the energy difference between the  $\text{Eu}^{4+/3+}$  and  $\text{Pr}^{4+/3+}$  CTL energies from Eq. (3).

The lengths of the upward pointing arrows starting at the  $\text{Eu}^{3+/2+}$  CTL energy in Fig. 8, and also in the corresponding VRBE diagrams in Fig. SI-3 until SI-14, represent the  $\Delta E_i^e(\text{Eu}^{2+})$  e-trap depths from Table 4. The endpoints of the arrows, indicated by solid bullet data symbols, are the energies on the left hand side of Eq. (15) which should ideally coincide with the CB-bottom. Often, they are surprisingly close to  $E_C$  with strongest deviation for  $\text{NaLuGeO}_4$  (Fig. SI-6a) and  $\text{Gd}_3\text{Al}_2\text{Ga}_3\text{O}_{12}$  (Fig. SI-9a). The endpoint energies for e-traps other than that of  $\text{Eu}^{3+}$  can be found in the VRBE diagrams of Fig. SI-3 until Fig. SI-14. The endpoint energies averaged over different lanthanides for each compound are shown as open bullet data symbols in the stacked diagram of Fig. 8. Again, most endpoints are within few tenths of an eV from  $E_C$ . Relatively large deviations (up to 0.3–0.4 eV) occur for the compounds  $\text{LiLuSiO}_4$  (Fig. SI-7b),  $\text{LiYSiO}_4$  (Fig. SI-8a),  $\text{Ca}_3\text{Si}_2\text{O}_7$  (Fig. SI-8b),  $\text{MgO}$  (Fig. SI-12b),  $\text{SrSi}_2\text{AlO}_2\text{N}_3$  (Fig. SI-13a), and  $\text{Ca}_2\text{Si}_5\text{N}_8$  (Fig. SI-14b). This may signal errors in the used parameters  $E^{ex}$  and  $E^{CT}$  for VRBE diagram construction. Particularly,  $E^{ex} = 6.78$  eV for  $\text{Ca}_3\text{Si}_2\text{O}_7$  from [49] is  $\approx 0.5$  eV lower than usually reported for a pyro-silicate compound. The same compound also showed a quenching energy barrier  $\Delta E_q$  for  $\text{Eu}^{2+}$  5d-4f emission that deviates about 0.5 eV from the VRBE diagram prediction in the study of [5]. An 0.5 eV larger  $E^{ex}$  will therefore bring the VRBE diagram consistent with both the observed e-trap depths and quenching energy barrier.

The length of the downward pointing arrows starting at the  $\text{Pr}^{4+/3+}$  CTL energy in Fig. 8 represent the  $\Delta E_i^h(\text{Pr}^{4+})$  h-trap depths from Table 5. The endpoints are again indicated by solid bullet data symbols and are equivalent to the energies on the left hand side of Eq. (16).

The same can be seen in the VRBE diagrams of Fig. SI-3 until SI-14. Ideally, they should coincide with the valence band top  $E_V$  as expressed with Eq. (16). However, apart from  $\text{La}_2\text{O}_2\text{S}$  they always end at higher energy. This can be explained partly by the temperature dependence of CTL energies. Eq. (8) expresses that with increase of temperature the CTL energy difference between the VB-top and the  $\text{Eu}^{3+/2+}$  CTL decreases. Assuming a similar dependence for the energy difference between the VB-top and the  $\text{Pr}^{4+/3+}$  CTL energy one obtains

$$\Delta E_i^h(\text{Pr}, 293\text{K}) = \Delta E_i^h(\text{Pr}, T_m) + 6 \times 10^{-4}(T_m - 293) \quad (17)$$

The open bullet symbols near  $E_V$  in the stacked diagram of Fig. 8 are the endpoint energies when Eq. (17) is applied. The situation improves somewhat but still the endpoint energies tend to be located significantly above the VB-top. This was noticed earlier and attributed to the phenomenon that a hole state at the VB-top tends to be shared by a few neighbouring anions that relax around the hole thus forming a self-trapped hole centre. The self-trapped hole state may then, depending on type of compound, be located 0.3–0.6 eV above the VB-top. It can migrate through the lattice by a hopping type of motion to eventually recombine with the trapped electron. Other possible explanations are suggested by Eq. (16). Perhaps the  $U$ -value is systematically underestimated or the energy of the  $\text{Eu}^{3+}$  CT-band is systematically overestimated. Although the latter would according to Eq. (15) also affect the endpoint energies of the e-trap.

#### 4.3. Systematic errors and mismatches in VRBE diagrams

Ideally the quenching energy barriers  $\Delta E_q$  derived from lanthanide luminescence quenching data and the e-trap and h-trap depths  $\Delta E_i$  derived with TL-recordings should agree with what is read from a VRBE diagram. Column 6 of Table 2 and Eq. (11) shows the offsets or mismatch energies in  $\Delta E_q$  for the lanthanides studied in [5]. These offsets are used in Fig. 11 to illustrate how the results from quenching data mismatch with predictions from the VRBE schemes. The figure shows a VRBE scheme for a hypothetical compound, and the only relevant information are the averaged mismatch energies. For example the 0.3 eV wide shaded bar around the solid bullet data point for  $\text{Tb}^{3+}$  at 0.5 eV below  $E_C$  indicates that, averaged over compounds, the quenching energy barrier  $\Delta E_q$  added to the  $^5D_4$  level location of  $\text{Tb}^{3+}$  has an endpoint energy of  $(0.50 \pm 0.15)$  eV below  $E_C$ . Information from Table 2 for quenching data for  $\text{Ce}^{3+}$ ,  $\text{Pr}^{3+}$ ,  $\text{Eu}^{3+}$  are also shown. Furthermore, we have added in the diagram the results from the hole trap depths of  $\text{Pr}^{4+}$  and  $\text{Tb}^{4+}$  that on average have an endpoint energy 0.23 eV and 0.24 eV above  $E_V$ , and the e-trap depths of divalent lanthanides that on average are an insignificant amount of 0.02 eV different from  $E_C$ .

There are errors in the derived trapping depths from TL-glow peaks due to errors in the used value for  $s$ , the value for  $T_m$ , and the assumption of a symmetrical distribution in trap depths. A factor of 100 error in  $s$  or 20 K error in  $T_m$  contributes 0.05 eV error in the derived trap depths. Errors of 0.1 eV are present in the  $U$ ,  $E^{ex}$  and  $E^{CT}$  parameters needed for VRBE diagram construction. Considering this, the mismatch energies in Fig. 11 are all quite acceptable. An argument that the  $U$ -values are systematically underestimated by a few 0.1 eV will lower the mismatches near the VB-top but those for the electron transitions from  $\text{Ce}^{3+}$ ,  $\text{Pr}^{3+}$  and  $\text{Tb}^{3+}$  will also lower further below the CB-bottom. So this argument will not provide better overall agreement. In VRBE diagram construction, the energy at the maximum of the  $\text{Eu}^{3+}$  CT-band is used to place the  $\text{Eu}^{3+/2+}$  CTL above  $E_V$ . This assumption may also have a systematic error. Perhaps one should take an energy slightly beyond or before the maximum. Such error would raise or lower all mismatch energies in Fig. 11 with the same amount. Again, that will not lead to an overall better agreement. Perhaps the differences are supposed to be so. We already discussed the possibility of hole migration by means of a trapped hole centre to explain the

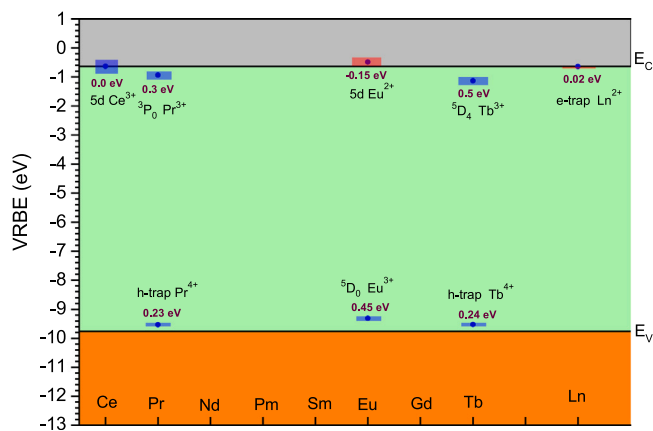


Fig. 11. VRBE scheme of a hypothetical compound. Solid bullet data points mark the average energy differences between energies derived from thermal quenching or TL data and VRBE schemes. The width of the shaded bars indicate error margins. Those near the CB-bottom are obtained from thermal excitation of electrons from  $\text{Ln}^{2+}$  ground states in TL-recordings or from excited states ( $5d$  for  $\text{Ce}^{3+}$  and  $\text{Eu}^{2+}$ ,  $^3P_0$  for  $\text{Pr}^{3+}$  and  $^5D_4$  for  $\text{Tb}^{3+}$ ) in thermal luminescence quenching studies. Those near the VB-top are from thermal excitation of holes from the ground state in the case of  $\text{Pr}^{4+}$  and  $\text{Tb}^{4+}$  or from the  $^5D_0$  excited state in the case of  $\text{Eu}^{3+}$ .

on average 0.23 eV mismatch for  $\text{Pr}^{4+}$ . In the case of quenching or  $5d$ - $4f$  emission for  $\text{Ce}^{3+}$  and  $\text{Eu}^{2+}$ , lattice relaxation and Stokes shift contribute to the mismatch energies.

## 5. Summary and conclusions

This work has collected TL-data on lanthanides in inorganic compounds from the archival literature with the aim to extract information on lanthanide electron or hole trap depths. Since there is always a distribution in trap depths, a method that derives trap depths from the temperature  $T_m$  where the glow peaks have maximal intensity was regarded as most appropriate. Information on 36 different compounds were found, and for each compound the room temperature VRBE diagram has been constructed using the RCS-model. The change in electron trap depth with changing type of  $\text{Ln}^{2+}$  follows the shape of the  $\text{Ln}^{3+/2+}$  CTL curve usually within 0.1 eV, and this provides further evidence that the variation in CTL energy as obtained with the RCS-model is correct. The electron trap depths added to the  $\text{Ln}^{2+}$  CTL energy is usually within 0.1 eV from the CB-bottom. In cases where compounds or specific  $\text{Ln}^{2+}$  show large deviation, there is strong suspicion that there are errors in the construction parameters of the VRBE diagram or that a glow peak has been wrongly assigned to a lanthanide electron trap. The hole trap depth of  $\text{Pr}^{4+}$  and  $\text{Tb}^{4+}$  subtracted from the  $\text{Pr}^{4+/3+}$  and  $\text{Tb}^{4+/3+}$  CTL energy appears always significantly, i.e. 0.3–0.5 eV, above the VB-top. This is partly attributed to a hole trap depth reduction at the temperature  $T_m$ . Self trapped hole centre creation has also been suggested as possible cause.

The results on trap depths  $\Delta E_t$  from TL data from this work together with data on the energy  $\Delta E_q$  from thermal quenching of lanthanide luminescence from [5] was compared with the energies as predicted from the VRBE diagrams. There are several error contributions; (1) the parameters  $E^{ex}$ ,  $E^{CT}$ , and  $U$  for room temperature VRBE diagram construction may each contain  $\pm 0.1$  eV error, (2) it is assumed that the relaxation fractions  $f(Q, A)$  are the same for each lanthanide and the same for each individual lanthanide-anion bond in the compound. This is not necessarily the case, and it will then distort the lanthanide CTL zigzag curves, (3) lattice relaxation after luminescence excitation and after a valence change of a lanthanide by charge carrier transfer is not accounted for in VRBE diagram construction. (4) An error of 20 K in  $T_m$  or a factor of 100 error in the frequency factor  $s$  leads to typically

0.05 eV error in the trap depth. This work has shown that the thermal quenching data and charge carrier trapping data are consistent with the predictions from the VRBE schemes. Deviations are of the order of 0.1 to 0.3 eV, and considering the various error contributions one may not expect to have reached better agreement. This means that the method of VRBE diagram construction has been further confirmed with the results of this work.

## CRedit authorship contribution statement

**Pieter Dorenbos:** Writing – review & editing, Writing – original draft, Methodology, Investigation, Formal analysis, Conceptualization.

## Declaration of competing interest

The authors declare that they have no known competing financial interests or personal relationships that could have appeared to influence the work reported in this paper.

## Data availability

Data will be made available on request.

## Appendix A. Supplementary data

Supplementary material related to this article can be found online at <https://doi.org/10.1016/j.omx.2024.100316>.

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